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Application/Control	No.	-

Applicant(s)/Patent under Reexamination

10/743,540

SUNAGA ET AL.

Examiner

Elias B. Hiruy

2837

	SEARCHED			
Class	Subclass	Date	Examiner	
318	34	10/26/2005	, EH	
318	599	10/25/2005	EH	
318	59-60	10/26/2005	EH	
318	54-56	10/26/2005	ЕН	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
318	62-63	10/26/2005	EH	
318	54-56	10/26/2005	EH	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted with David Martin regarding applicant amendment.	10/25/2005	EH
Searched East: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	10/26/2005	EH
318/801.ccls. and (air adj3 condition\$4) (air\$1condition\$4) (aircondition\$4))	10/26/2005	EH
318/62-63.ccls. and ((air adj3 condition\$4) (air\$1condition\$4) (aircondition\$4))	10/26/2005	EH
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